

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1. (Currently Amended) An apparatus for validating the presence of an authorized consumable of a device, the consumable having a first authentication integrated circuit that is configured to store a secret key K_A and state data on the consumable, the apparatus comprising:
 - a second integrated circuit which stores a public key K_T and is configured to hold a random number function which returns random number R , the second integrated circuit being configured to apply a function $F[R]$ to return $F_{KT}[R]$, based on the public key K_T , and the first integrated circuit being configured to apply a function $D[F_{KT}[R]]$ to return $D_{KA}[F_{KT}[R]]$, based on the secret key K_A ; and
 - a control system which is configured to request $F_{KT}[R]$ from the second integrated circuit, to request $D_{KA}[F_{KT}[R]]$ from the first integrated circuit to obtain R_A , and to compare R returned by the second integrated circuit with R_A returned by the first integrated circuit.
2. (Cancelled)
3. (Previously Presented) An apparatus as claimed in claim 1, in which the second integrated circuit is configured to advance R to next in sequence with each invocation of the random number function.
4. (Previously Presented) An apparatus as claimed in claim 3, in which the second integrated circuit includes a linear feedback shift register which holds the random number function.
5. (Cancelled).
6. (Currently Amended) A method of validating the presence of an authorized consumable of a device, the method comprising the steps of:
 - storing a public key, K_T , in an integrated circuit of the device and storing a secret key, K_A , in an integrated circuit of the consumable which also stores state data on the consumable;
 - generating a random number R with the integrated circuit of the device;
 - applying a function $F[R]$ to R using K_T at the integrated circuit of the device to return

$F_K[R]$ and applying a function $D[F_K[R]]$ to $F_K[R]$ using K_A at the integrated circuit of the consumable to return R_A ; and

comparing R from the integrated circuit of the device with R_A from the integrated circuit of the consumable.